XRD: X-ray diffraction

X-ray diffraction is analytical method based on inspection of crystalline structure of samples. Applications:

> Metallurgy, Mineralogy Powders, Pigments, Polymers Surface layers Strain mapping

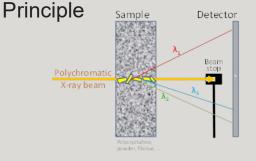
DETECTOR IS A KEY

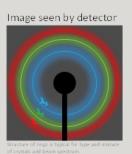
The traditional XRD uses monochromatic X-rays which make the apparatus large and slow. ADVACAM's spectral camera based on Timepix3 chip with high resolution makes it fast and compact:

The high resolution detector can be placed close to the sample covering large solid angle -> fast data accumulation.

The polychromatic X-ray beam can be used with ADVACAM's energy dispersive detectors -> system is faster, smaller, much less complex.

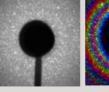
Broad energy range (3 - 150 keV): Even heavy samples can be transmitted (stainless steel, heavy metals and minerals).

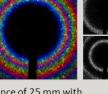




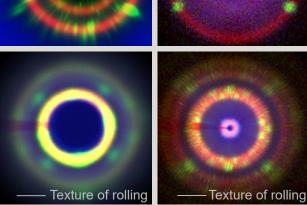
Recalculate & sum bins:

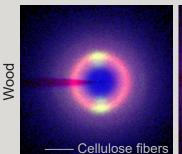
Common detector Timepix3 detector: energy bins per 1 keV





Silicon powder in distance of 25 mm with polychromatic X-ray beam of 0.5 x 0.5 mm at 80 kVp.





Examples

Pb+Zn ore

Stainless steel 2 mm

MINIPIX TPX3

Silicon crystal

Fiber orientation

ADVAPIX TPX3

SUITABLE CAMERAS

Readout chip type Sensor material Pixel size Readout speed Interface Dimensions Weight



Timepix 3 Si or CdTe 55 x 55 um 2.35 Million hits/s USB 2.0 (High-Speed) 80 x 21 x 14 mm 30 g



Timepix 3 Si or CdTe 55 x 55 um 40 Million hits/s USB 3.0 125 x 79 x 25.5 mm 503 g

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